

<b>Notice of References Cited</b>	Application/Control No. 10/664,000	Applicant(s)/Patent Under Reexamination MIR, KALIM	
	Examiner FRANK W. LU	Art Unit 1634	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,268,146 B1	07-2001	Shultz et al.	435/6
*	B	US-5,256,536	10-1993	Miyada et al.	435/6
	C	US-			
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	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	The definition for scanning probe microscopy from Wikipendia, the free encyclopedia. Printed on August 3, 2008.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.